

Application/Control N	10.
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10/814,853 Examiner

Habte Mered

Applicant(s)/Patent under Reexamination

LI ET AL.

Art Unit

2616

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	536	11/8/2007	нм
370	480	11/8/2007	НМ
370	208	11/8/2007	НМ
370	319	11/8/2007	нм
370	542	11/8/2007	нм
375	260,340	11/8/2007	нм

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Searched EAST DB:USPAT,USPGPUB, JPO, and EPO	11/8/2007	НМ
Searched IEEE	11/8/2007	нм
Searched Palm Inventor's DB	11/8/2007	НМ
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